



Future Normal in Semiconductor

2025-02-14(금), 09:00-10:45

좌장: 추후업데이트 예정

K. Memory (Design & Process Technology) 분과

[FA1-K] Security Applications and Reliability of Emerging Memory

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| <p>FA1-K-1 09:00-09:15</p> | <p>Designing Memristive Baffle Systems via Material and Simulation Co-Design and Their Implementation for Enhancing Synaptic Linearity Characteristics</p> <p>Eun Young Kim, Juseong Park, Sumin Ju, Woojoon Park, Woon Hyung Cheong, Myeongchan Ko, and Kyung Min Kim KAIST</p> |
| <p>FA1-K-2 09:15-09:30</p> | <p>Leakage Current Estimation of CVD-grown MoS₂ Based 2TOC DRAM and Retention Limitation by Read Transistor Degradation</p> <p>Changjun Lee^{1,3}, Jisoo Seok², and Jiwon Chang^{1,2,3}</p> <p>¹Department of System Semiconductor Engineering, Yonsei University, ²Department of Materials Science and Engineering, Yonsei University, ³BK21 Graduate Program in Intelligent Semiconductor Technology</p> |
| <p>FA1-K-3 09:30-09:45</p> | <p>In-Series Phase-Change Memory Pair for Enhanced Data Retention and Large Window in Automotive Application</p> <p>Sejeung Choi¹ and Sangbum Kim^{1,2,3}</p> <p>¹Department of Materials Science and Engineering, College of Engineering, Seoul National University, ²Research Institute of Advanced Materials, Seoul National University, ³Inter-university Semiconductor Research Center, Seoul National University</p> |
| <p>FA1-K-4 09:45-10:00</p> | <p>True Random Number Generator Using Random Telegraph Noise Signal of Memristor with Tolerance</p> <p>Dayeon Yu^{1,2} and Hyungjin Kim^{1,2}</p> <p>¹Division of Materials Science and Engineering, Hanyang University, ²Department of Semiconductor Engineering, Hanyang University</p> |
| <p>FA1-K-5 10:00-10:15</p> | <p>Heterogeneous Data Clustering and Outlier Detection with Multifunctional Memristive Array</p> <p>Dong Hoon Shin^{1,2}, Sunwoo Cheong^{1,2}, Néstor Ghenzi^{1,2}, and Cheol Seong Hwang^{1,2}</p> <p>¹Department of Materials Science and Engineering, Seoul National University, ²Inter-University Semiconductor Research Center, Seoul National University</p> |



제 32회 한국반도체학술대회

The 32nd Korean Conference on Semiconductors

2025년 2월 12일(수)-14일(금) | 강원도 하이원리조트

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| <p>FA1-K-6 10:15-10:30</p> | <p>True Random Number Generator Using Memcapacitor based on Flash Cell Hwiho Hwang^{1,2}, Sangwook Youn^{1,2}, and Hyungjin Kim^{1,2} ¹Division of Materials Science and Engineering, Hanyang University, ²Department of Semiconductor Engineering, Hanyang University</p> |
| <p>FA1-K-7 10:30-10:45</p> | <p>Enhanced Cryogenic Stability and Endurance of CMOS-Compatible HfZrO₂ FeCAPs with Optimized WO Buffer layer Eunjin Kim and Jiyong Woo School of Electronic and Electrical Engineering, Kyungpook National University</p> |